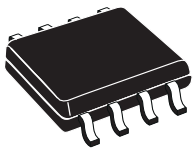
STS2NF100

N-CHANNEL 100V - 0.23 Ω - 6A SO-8
STripFET™ II POWER MOSFET

TYPE	V_{DSS}	$R_{DS(on)}$	I_D
STS2NF100	100 V	<0.26 Ω	6 A

- TYPICAL $R_{DS}(on)$ = 0.23 Ω
- EXCEPTIONAL dv/dt CAPABILITY
- 100 % AVALANCHE TESTED
- APPLICATION ORIENTED CHARACTERIZATION



SO-8

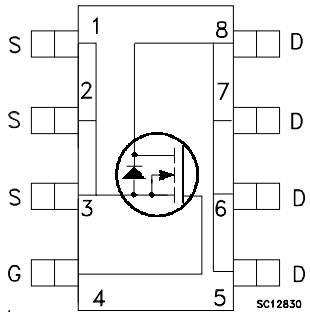
DESCRIPTION

This MOSFET series realized with STMicroelectronics unique STripFET process has specifically been designed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced high-efficiency, high-frequency isolated DC-DC converters for Telecom and Computer applications. It is also intended for any applications with low gate drive requirements.

APPLICATIONS

- HIGH-EFFICIENCY DC-DC CONVERTERS
- UPS AND MOTOR CONTROL

INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source Voltage (V_{GS} = 0)	100	V
V_{DGR}	Drain-gate Voltage (R_{GS} = 20 kΩ)	100	V
V_{GS}	Gate- source Voltage	± 20	V
I_D(•)	Drain Current (continuous) at T_C = 25°C	2	A
I_D	Drain Current (continuous) at T_C = 100°C	1.3	A
I_{DM}(••)	Drain Current (pulsed)	8	A
P_{tot}	Total Dissipation at T_C = 25°C	2.5	W
	Derating Factor	0.016	W/°C
dV/dt (1)	Peak Diode Recovery voltage slope	40	V/ns
E_{AS} (2)	Single Pulse Avalanche Energy	200	mJ
T_{stg}	Storage Temperature	-65 to 175	°C
T_j	Max. Operating Junction Temperature		

(••) Pulse width limited by safe operating area.
(•) Current limited by the package

(1) I_{SD} ≤2A, di/dt ≤300A/µs, V_{DD} ≤ $V_{(BR)DSS}$, T_j ≤ T_{JMAX}
(2) Starting T_j = 25 °C, I_D = 3A, V_{DD} = 50V

THERMAL DATA

$R_{thj\text{-}amb}$	(*)Thermal Resistance Junction-ambient	50	°C/W
T_j	Thermal Operating Junction-ambient	-55 to 150	°C
T_{stg}	Storage Temperature	-55 to 150	°C

(*) Mounted on FR-4 board ($t \leq 10$ sec.)

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	I_D = 250 µA, V_{GS} = 0	100			V
I_{DSS}	Zero Gate Voltage Drain Current (V_{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating T_C = 125°C			1 10	µA µA
I_{GSS}	Gate-body Leakage Current (V_{DS} = 0)	V_{GS} = ± 20 V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS} I_D = 250 µA	2	3	4	V
$R_{DS(on)}$	Static Drain-source On Resistance	V_{GS} = 10 V I_D = 1 A		0.23	0.26	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g_{fs} (*)	Forward Transconductance	V_{DS}>$I_{D(on)}$x$R_{DS(on)max}$ I_D = 1 A		0.5		S
C_{iss} C_{oss} C_{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V_{DS} = 25V, f = 1 MHz, V_{GS} = 0		280 45 20		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on Delay Time Rise Time	V_{DD} = 50 V I_D = 1 A R_G = 4.7 Ω V_{GS} = 10 V (Resistive Load, Figure 3)		6 10		ns ns
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V_{DD}= 80V I_D= 1A V_{GS}=10V		10 2.5 4		nC nC nC

SWITCHING OFF

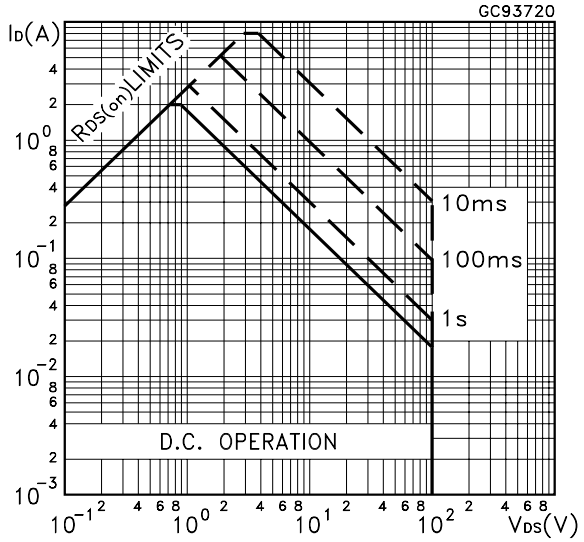
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$ t_f	Turn-off Delay Time Fall Time	V_{DD} = 50 V I_D = 1 A R_G = 4.7Ω, V_{GS} = 10 V (Resistive Load, Figure 3)		20 3		ns ns
$t_{r(Voff)}$ t_f t_c	Off-Voltage Rise Time Fall Time Cross-over Time	V_{clamp} = 80 V I_D = 1 A R_G = 4.7Ω V_{GS} = 10 V (Inductive Load, Figure 5)		19 8 15		ns ns ns

SOURCE DRAIN DIODE

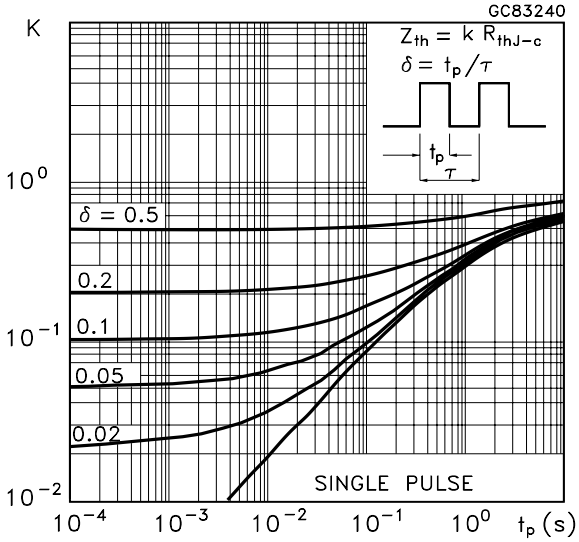
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} I_{SDM} (•)	Source-drain Current Source-drain Current (pulsed)				6 24	A A
V_{SD} (*)	Forward On Voltage	I_{SD} = 2 A V_{GS} = 0			1.3	V
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I_{SD} = 2 A di/dt = 100A/µs V_{DD} = 10 V T_j = 150°C (see test circuit, Figure 5)		70 175 5		ns nC A

(*)Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

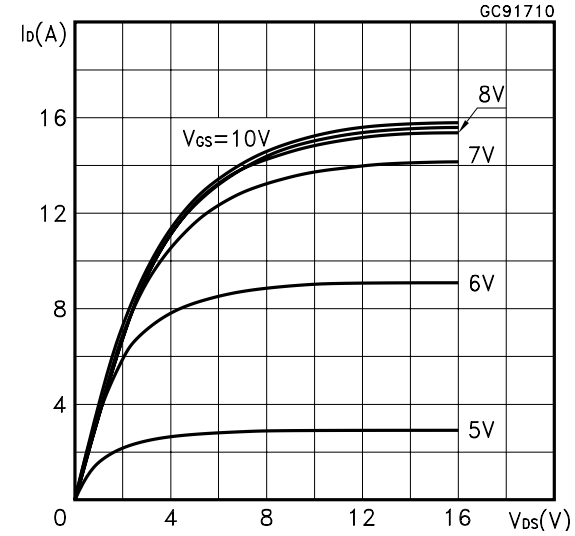
Safe Operating Area



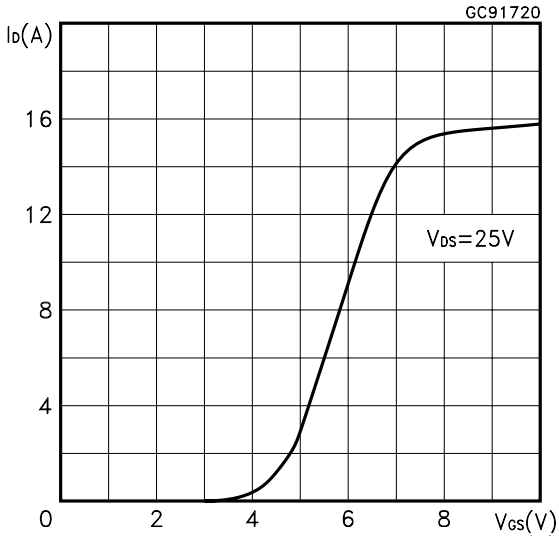
Thermal Impedance



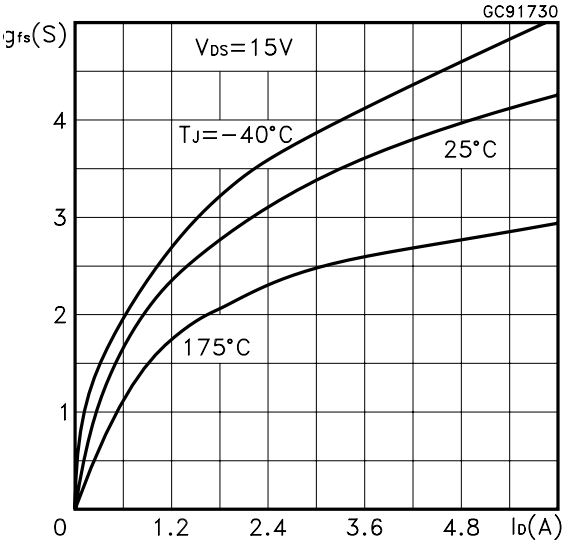
Output Characteristics



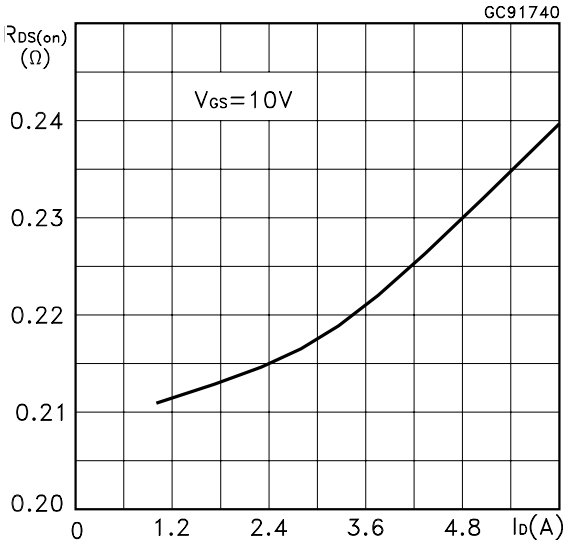
Transfer Characteristics



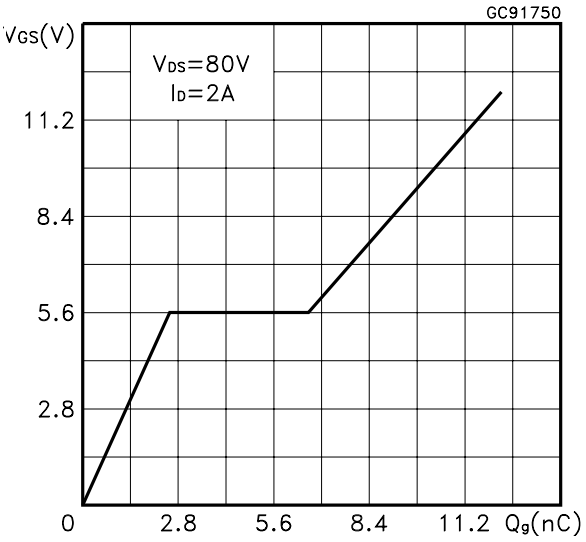
Transconductance



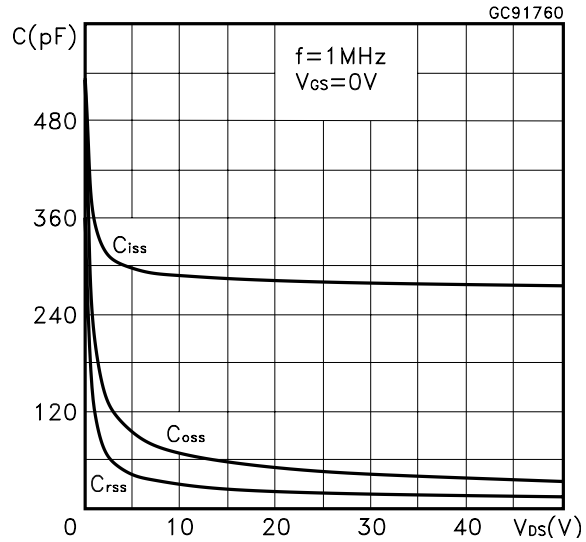
Static Drain-source On Resistance



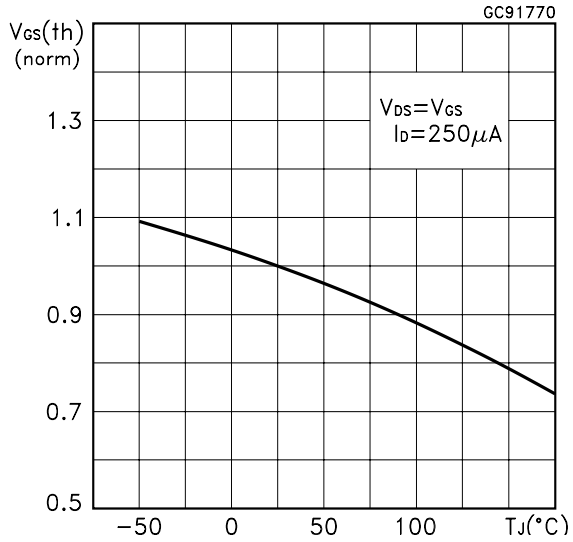
Gate Charge vs Gate-source Voltage



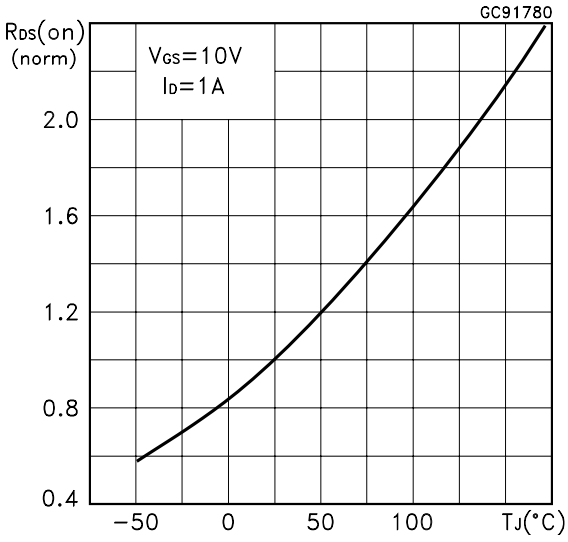
Capacitance Variations



Normalized Gate Threshold Voltage vs Temperature



Normalized on Resistance vs Temperature



Source-drain Diode Forward Characteristics

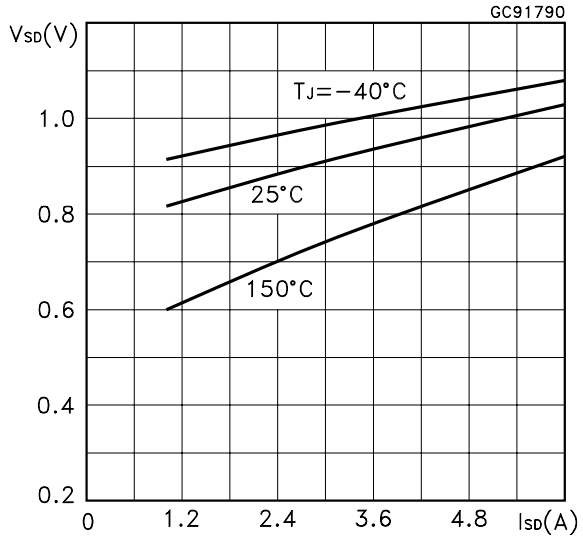


Fig. 1: Unclamped Inductive Load Test Circuit

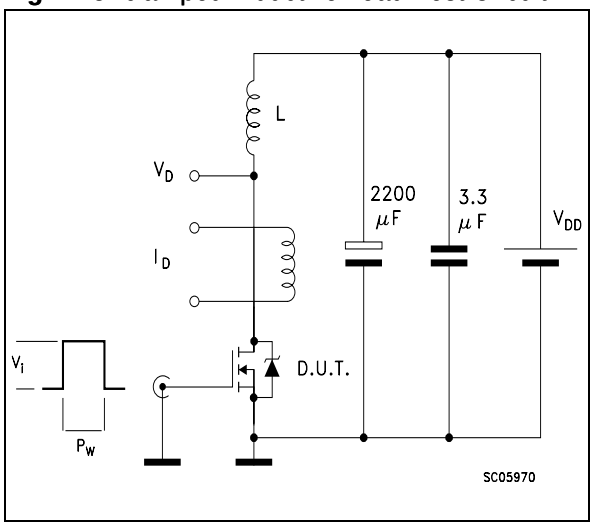


Fig. 2: Unclamped Inductive Waveform

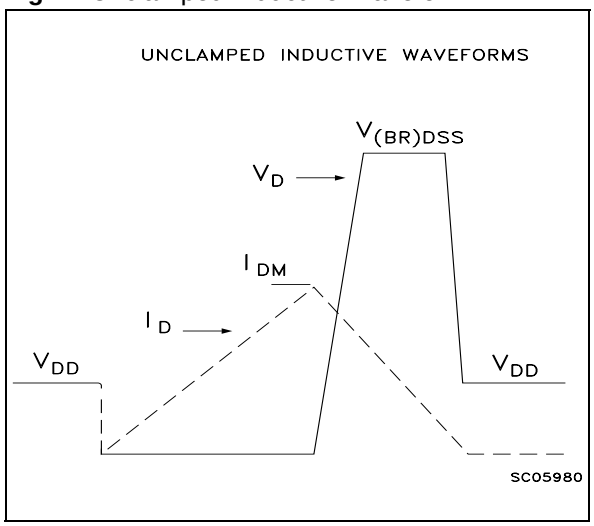


Fig. 3: Switching Times Test Circuits For Resistive Load

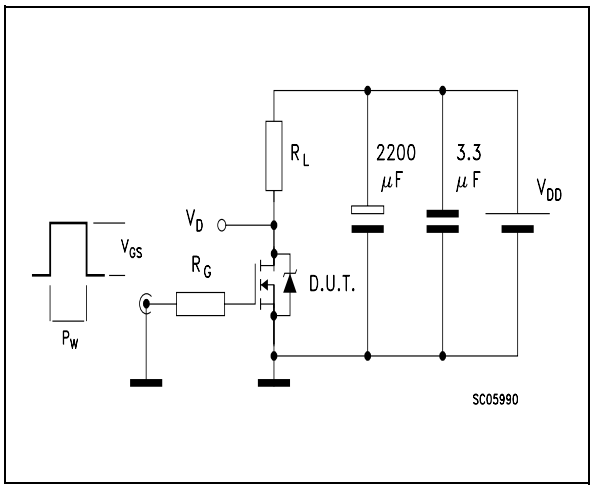


Fig. 4: Gate Charge test Circuit

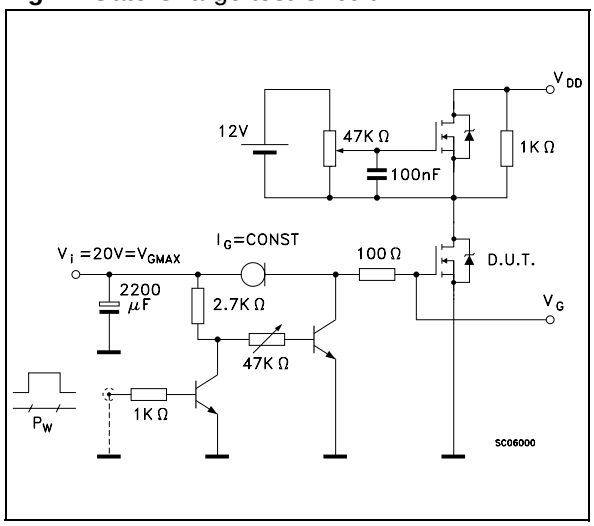
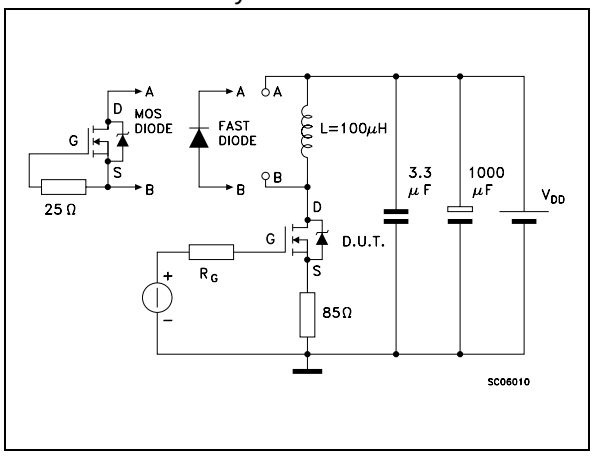
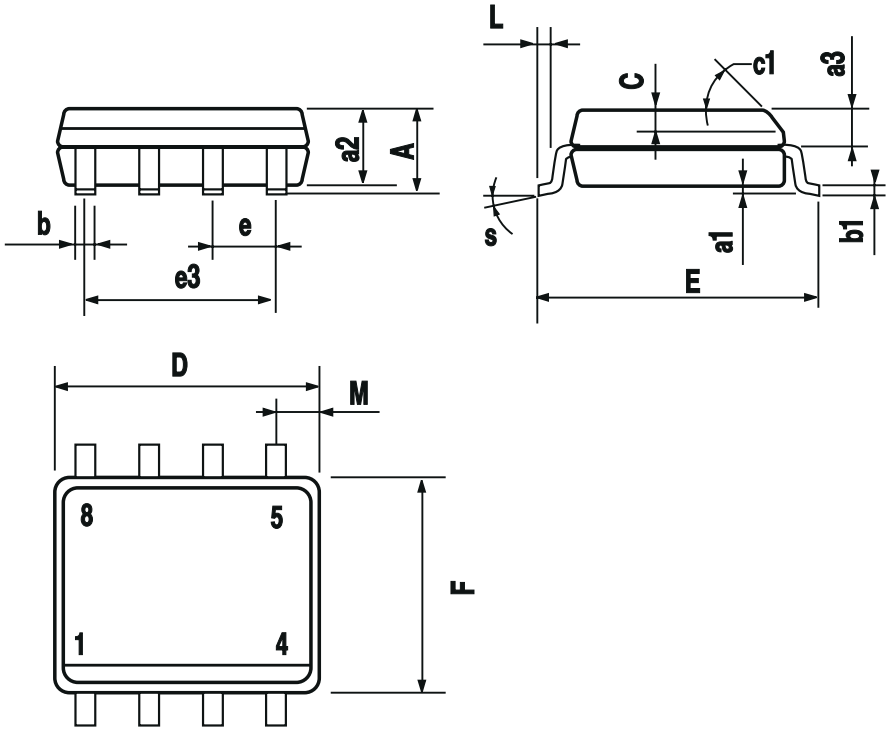


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



SO-8 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
C	0.25		0.5	0.010		0.019
c1	45 (typ.)					
D	4.8		5.0	0.188		0.196
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
M			0.6			0.023
S	8 (max.)					



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